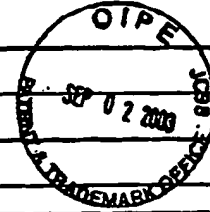


INFORMATION DISCLOSURE CITATION

Atty. Docket No.	03180.0324	Serial No.	10/602,670
Applicants	Shunko MAGOSHI et al.		
Filing Date	June 25, 2003	Group:	



U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
De	5,278,421	01/11/1994	Yoda et al.	250	492.22	
ke	6,243,487 B1	06/05/2001	Nakajima	382	144	

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	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
De	Fumio MURAI et al., "Fast proximity effect correction method using a pattern area density map", J. Vac. Sci. Technol. B 10(6), Nov/Dec 1992, pp. 3072-3076

Examiner	ZIA R. HASHMI	Date Considered	4/7/04
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